

Search Notes

Application/Control No.

10/054,845

Examiner

Binh Q. Nguyen

Applicant(s)/Patent under
Reexamination

KATZ, SHACHAR

Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
370	238	11/23/2005	BQN
370	281	11/23/2005	BQN
370	235	11/23/2005	BQN
370	216	11/23/2005	BQN
370	254-256	11/23/2005	BQN
370	401-405	11/23/2005	BQN
370	222	11/23/2005	BQN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	11/23/2005	BQN
Consulted with SPE Wellington Chin	11/23/2005	BQN